U.S. DEPARTMENT OF COMMERCE U.S. PATENT AND TRADEMARK OFFICE

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INFORMATION DISCLOSURE	Filing Date	January 16, 2004			
STATEMENT BY APPLICANT	Applicant	Oren Eliezer et al.			
Form PTO-1449	Art Unit	2614			
	Examiner	Ramnandan P. Singh			
Sheet 1 of 1	Atty Docket No.	12411.0025;TI-35771			

U.S PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Date	Name	Class	Subclass	

FOREIGN PATENT DOCUMENTS

Examiner Cite Document Number	Date	Country	Name	т
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

	Examiner Initials	Cite No.	Author, title, date, page(s), etc.		
		1	Y, Sakinori, H. Mino, Y. Sekine, "Measurement of Phase Noise in High-Precision Oscillator Using PLL-Type Frequency Multiplier", Electronics and Communications Japan, Parl 2, Vol. 84, No. 8, pp. 64-70, 2001.		
2 M. Takamiya, H. Inohara, M. Mizuno, "On-Chip Jitter-Spectrum-Analyzer for Hi Speed Digital Designs", International Solid State Circuits Conf. (ISSCC) 2004.		M. Takamiya, H. Inohara, M. Mizuno, "On-Chip Jitter-Spectrum-Analyzer for High- Speed Digital Designs", International Solid State Circuits Conf. (ISSCC) 2004.			

Examiner	Date	
Signature	Considered	